Fig. 1

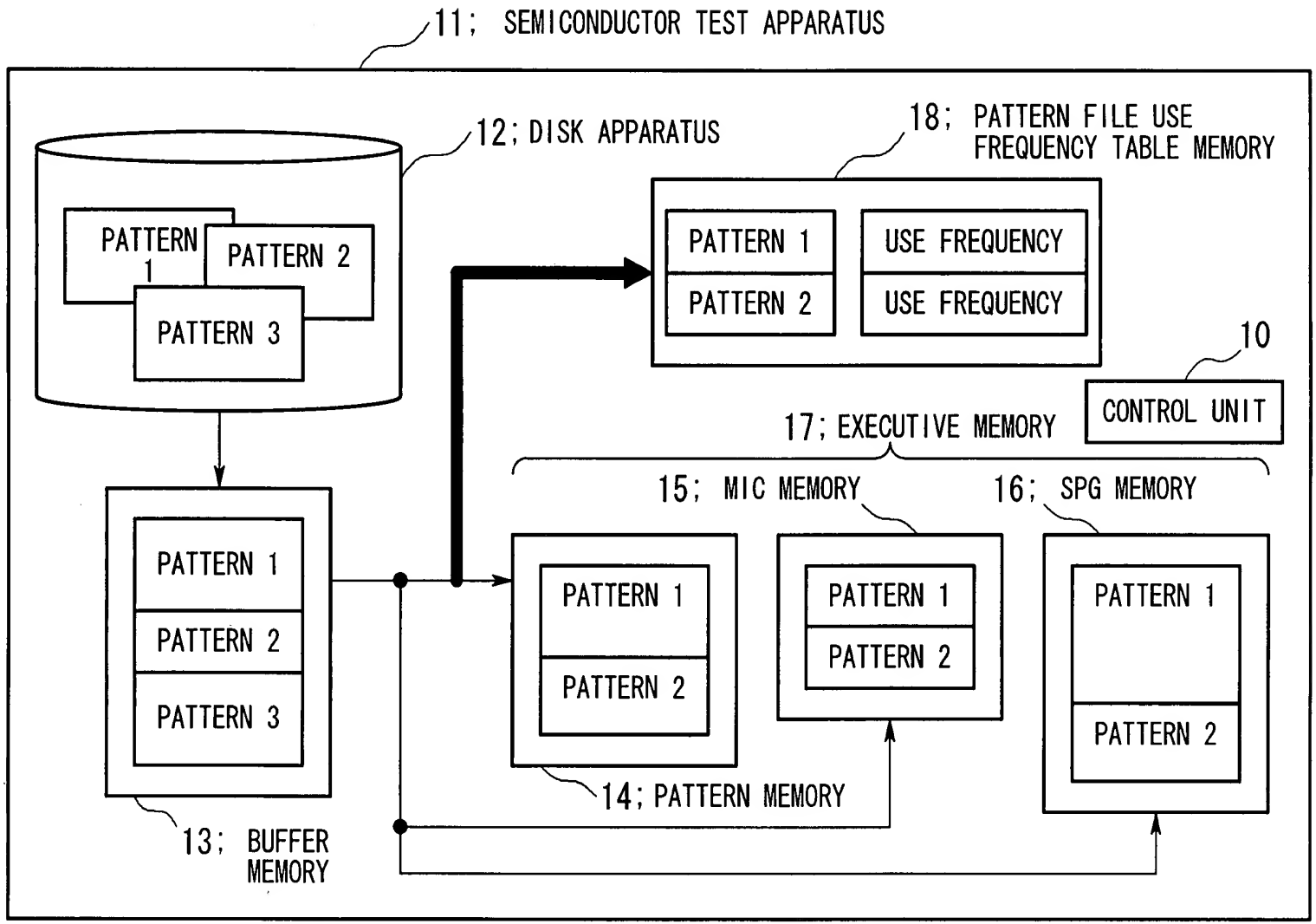
11; SEMICONDUCTOR TEST APPARATUS
12; DISK APPARATUS
PATTERN 1
PATTERN 2
PATTERN 3
18; PATTERN FILE USE FREQUENCY TABLE MEMORY
PATTERN 1
USE FREQUENCY
PATTERN 2
USE FREQUENCY
10
CONTROL UNIT
17; EXECUTIVE MEMORY
15; MIC MEMORY
16; SPG MEMORY
PATTERN 1
PATTERN 2
PATTERN 3
PATTERN 1
PATTERN 2
PATTERN 1
PATTERN 2
PATTERN 1
PATTERN 2
14; PATTERN MEMORY
13; BUFFER MEMORY

Fig. 2

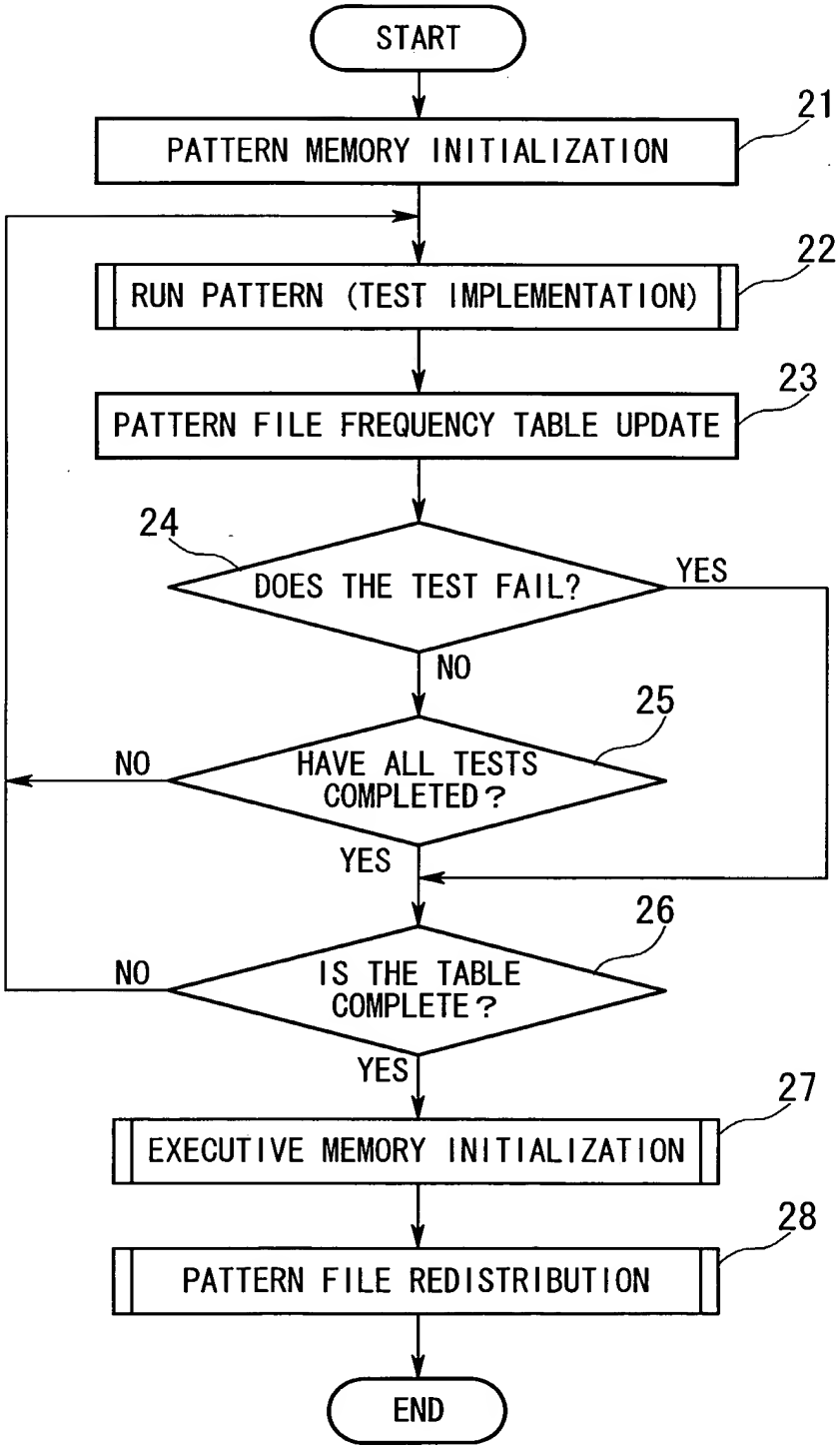
START
PATTERN MEMORY INITIALIZATION
21
RUN PATTERN (TEST IMPLEMENTATION)
22
PATTERN FILE FREQUENCY TABLE UPDATE
23
24
DOES THE TEST FAIL?
YES
NO
25
NO
HAVE ALL TESTS COMPLETED?
YES
26
NO
IS THE TABLE COMPLETE?
YES
EXECUTIVE MEMORY INITIALIZATION
27
PATTERN FILE REDISTRIBUTION
28
END

Fig. 3

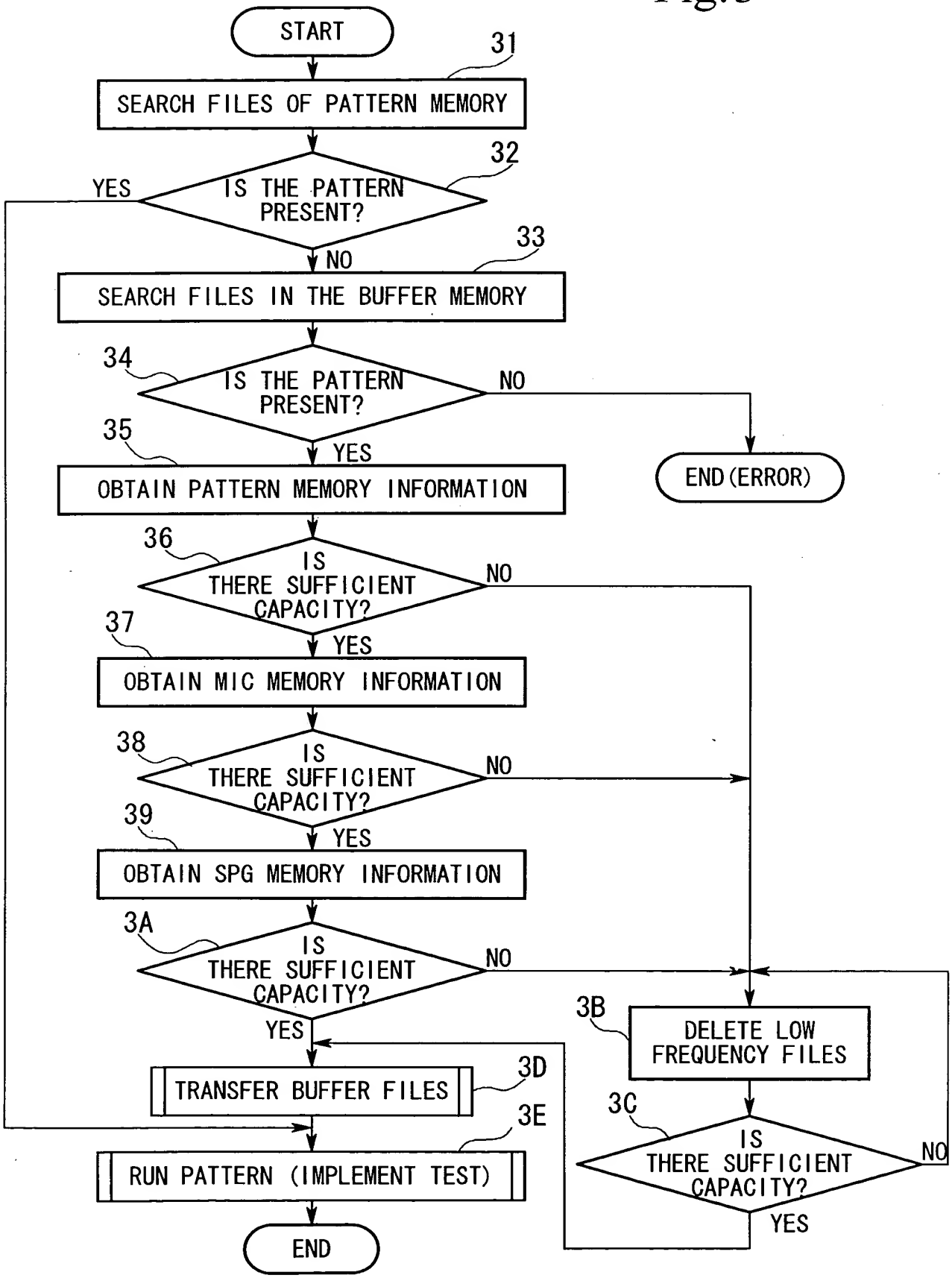
START
31
SEARCH FILES OF PATTERN MEMORY
32
IS THE PATTERN PRESENT?
YES
NO
33
SEARCH FILES IN THE BUFFER MEMORY
34
IS THE PATTERN PRESENT?
NO
END (ERROR)
YES
35
OBTAIN PATTERN MEMORY INFORMATION
36
IS THERE SUFFICIENT CAPACITY?
NO
YES
37
OBTAIN MIC MEMORY INFORMATION
38
IS THERE SUFFICIENT CAPACITY?
NO
YES
39
OBTAIN SPG MEMORY INFORMATION
3A
IS THERE SUFFICIENT CAPACITY?
NO
YES
3B
DELETE LOW FREQUENCY FILES
3C
IS THERE SUFFICIENT CAPACITY?
NO
YES
3D
TRANSFER BUFFER FILES
3E
RUN PATTERN (IMPLEMENT TEST)
END

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Fig. 4

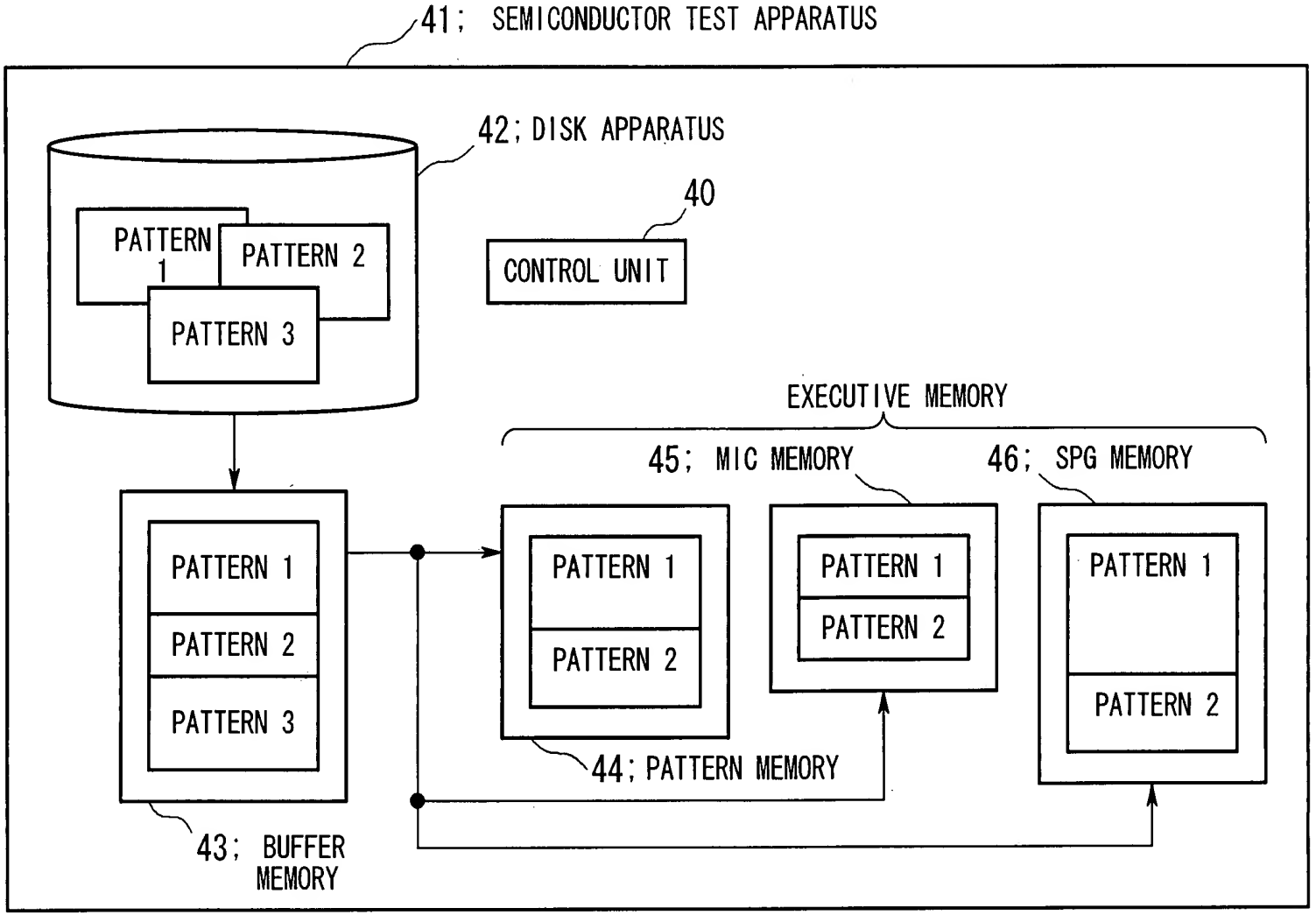
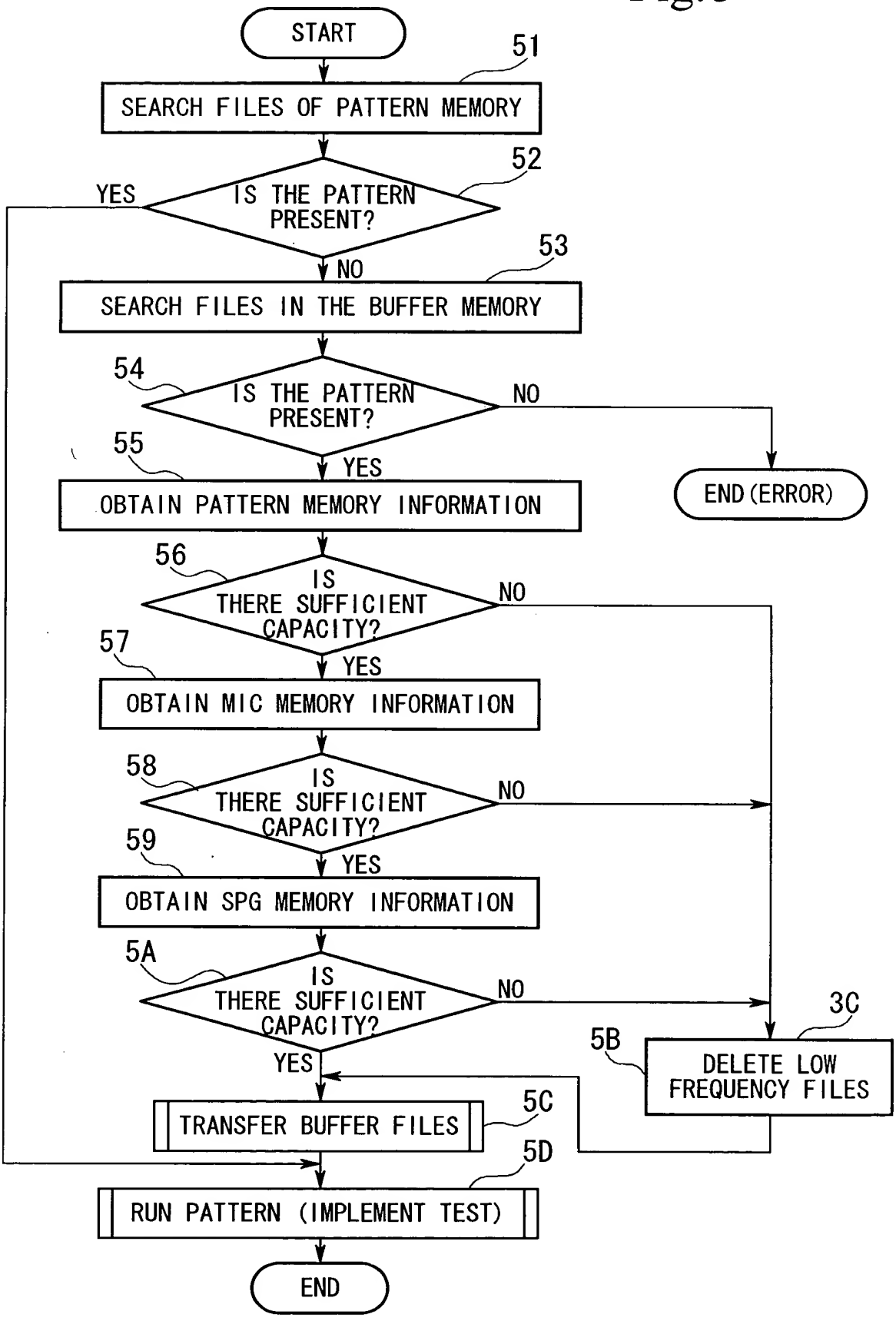


Fig. 5


START
51
SEARCH FILES OF PATTERN MEMORY
52
YES
IS THE PATTERN PRESENT?
NO
53
SEARCH FILES IN THE BUFFER MEMORY
54
IS THE PATTERN PRESENT?
NO
END (ERROR)
YES
55
OBTAIN PATTERN MEMORY INFORMATION
56
IS THERE SUFFICIENT CAPACITY?
NO
YES
57
OBTAIN MIC MEMORY INFORMATION
58
IS THERE SUFFICIENT CAPACITY?
NO
YES
59
OBTAIN SPG MEMORY INFORMATION
5A
IS THERE SUFFICIENT CAPACITY?
NO
YES
3C
5B
DELETE LOW FREQUENCY FILES
5C
TRANSFER BUFFER FILES
5D
RUN PATTERN (IMPLEMENT TEST)
END